

Energy dispersive x-ray CCD camera for PIXE-Kossel and imaging purposes

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PIXE – Kossel

- Each pixel of the CCD camera is an EDS detector (Energy Dispersive Spectrometer)
- Functioning equivalent to a SDD (silicon drift detector)
- Work in a large spectral range (5 eV 20 keV, depending on the CCD)
- Spectral resolution around 150 eV @ 6 keV
- Quantum efficiency > 10% over the whole spectral range
- Single-photon counting mode

• The pnCCD Color X-Ray Camera® (CXC) de PNDetector

• ANDOR iKon-M

- Back-illuminated deep-depletion
- Size of pixels
 - 13 µm x 13 µm (1024 x 1024)
- Pelletier cooling -80°C (low electronic noise)
- Spectral range
 - from 1 keV up to 20 keV
- Efficiency
 - >10%
- Software

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PIXE – Kossel

Principe of Kossel diffraction (GEXRF = grazing exit x-ray fluorescence)

- Generation characteristics x-rays
- Interference between emitted radiations
- Diffraction of the radiation emitted by the atoms of the multilayer by the multilayer structure itself under a given detection angle (Bragg for a periodic structure)

emission

emission

Multilayer structure

- Study of thin films
- Excitation
 - Protons (PIXE)
 - X-rays (XRF)
 - Electrons (XES)



Study of a Pt/Fe/Pt waveguide

Planar x-ray waveguide

- A "light" guiding material between two "heavy" cladding materials
- Total reflection





Simulations of the depth and angular distribution of the electric field and of the Kossel curve



Kossel curve: observation of the angular distribution of the emitted characteristic radiation

Modeling Kossel curves depth distribution of the emitting atoms

- Experimental process
- Be filter (protons dangerous for pixels)
- Bining 256 x 256 pixels (52 x 52 μm)
- No angular scan
- "Short" acquisition time, 2h

256 pixels Each pixel gives a spectrum sample LT AV EL Proton beam

Top view of the goniometric chamber











Structure with 5 layers Pt / PtFe / Fe / PtFe / Pt

	Thickness / Roughness (nm) (±0.05 nm)	Density (g/cm³)
Pt	3.83 / 0.57	bulk
Pt ₆₉ Fe ₃₁	1.62 / 0.90	16 ± 2
Fe	5.19 / 1.20	bulk
Pt ₆₉ Fe ₃₁	1.41 / 0.79	16 ± 2
Pt	10.25 / 0.39	bulk
Si substrate	- / 0.50	bulk

Interfaces PtFe ≈1.5 nm

PIXE – Kossel

- Full field x-ray fluorescence X (FF-XRF) in fact FF-PIXE!
- Spectral imaging without scanning of the beam or sample

- Isotropic radiation of the characteristic emission
- Need to put an optics between the emitting sample and the detector (CCD camera)
- So that one pixel of the CCD corresponds to one point of the sample





Spectral imaging



• First try with MPO at LCPMR with an x-ray tube (30 kV – 400 μA – 2h) FF-XRF



Visible image

- Copper grid
- Al sample holder
- Iron screws

grilles Ref (eV) (channel) spectre-arilles-40kV-30s 936.00 Cu L 226.00 y = 10.849 + 4.0875x R= 0.99999 Al Ka 1487.0 362.00 Si Ka 1740.0 423.00 5410.0 1318.0 Cr Ka Mn K 5890.0 1445.0 10000.0 Fe Ka 6399.0 1560.0 7058.0 Fe Kl 1721.0 Cu Ka 8040.0 1968.0 Cu Kt 8905.0 2169.0 9314 2276.0 Zn Ka 9572.0 2344.0 1000.0 ??? 10843 2650.0 100.0 1000 1500 2000 2500 3000 3500 4000 Ω 500 Channel

500 1000 1500 2000 2500 3000 Channel Emitted x-ray characteristic emissions





MPO

X-ray image Lot of scattered radiation Poor spatial resolution

Spectral imaging

• Project with a conical polycapilary



Spatial resolution depends on

- Size of pixels
- Diameter of capilaries
- Magnification
- Aberrations, ...





Magnification	20-40
D _{in} [mm]	0.42 ± 0.02
D _{out} [mm]	6.56-0.2
d_{in} [μ m]	0.5 ± 0.5
d_{out} [μ m]	7 ± 0.5
L [mm]	$53.34 - 0.5 \pm 0.2$

We expect

- Spatial resolution 1
- Large field of view

- 1 µm
- 1 mm x 1 mm
- Short acquisition time min to h
- Qualitative and quantitative mapping
- No scanning
- Study of geochemical markers of the environment obtained from biogenic carbonates (mollusc shells)

Conclusion

- X-ray energy dispersive CCD is a versatile instrument spectroscopy imaging
- PIXE-KOSSEL not only limited to periodic multilayers analysis of stacks of nanometer thin films
- Imaging possible without scanning
 - short acquisition time
 - large number of count quantitative maps
 - possibility to deploy this tools on electron microscopes



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MERCI THANK YOU

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